


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/672,200	PARIKH ET AL.	
	Examiner	Art Unit	
	Huyen Le	3751	

ISSUE CLASSIFICATION									
ORIGINAL					CROSS REFERENCE(S)				
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)			
401		183			401	261	25	195	
INTERNATIONAL CLASSIFICATION					604	3			
B	4	3	M	11/06					
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<i>Huyen Le</i> Huyen Le 3/1/2006 (Assistant Examiner) (Date)		<i>Justin Z</i> 3/3/06 JUSTINE R. YU SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700 (P Primary Examiner) (Date)		Total Claims Allowed: 1 O.G. Print Claim(s) 1 O.G. Print Fig. 1	
<i>Nicole P. Pineda</i> 3-3-06 (Legal Instruments Examiner) (Date)					

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant					<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47		
Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original
	1		31		61		91		121		181
	2		32		62		92		122		182
	3		33		63		93		123		183
	4		34		64		94		124		184
	5		35		65		95		125		185
	6		36		66		96		126		186
	7		37		67		97		127		187
	8		38		68		98		128		188
	9		39		69		99		129		189
	10		40		70		100		130		190
	11		41		71		101		131		191
	12		42		72		102		132		192
	13		43		73		103		133		193
	14		44		74		104		134		194
	15		45		75		105		135		195
	16		46		76		106		136		196
	17		47		77		107		137		197
	18		48		78		108		138		198
	19		49		79		109		139		199
	20		50		80		110		140		200
	21		51		81		111		141		201
	22		52		82		112		142		202
	23		53		83		113		143		203
	24		54		84		114		144		204
	25		55		85		115		145		205
	26		56		86		116		146		206
	27		57		87		117		147		207
	28		58		88		118		148		208
	29		59		89		119		149		209
	30		60		90		120		150		210